Performance of a test coil wound from defect-tolerant second-generation cable

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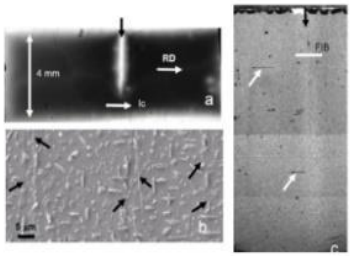
Outline

- Motivation: we need to overcome non-uniformity of 2G conductors
- Demonstration of defect tolerance
- Effect of compressive strain on reliability of YBCO layer
- Conclusion and future work

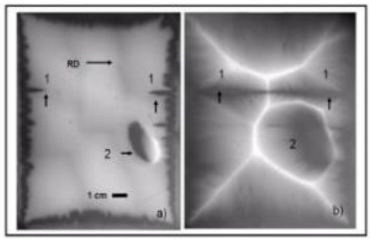
Uniformity challenge of 2G technology

Defects reduce continuous coupon length

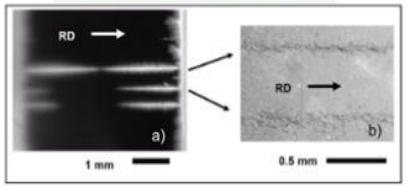
Across-tape defects



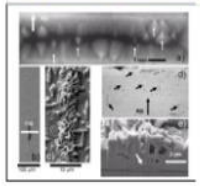
Deposition malfunction

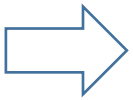


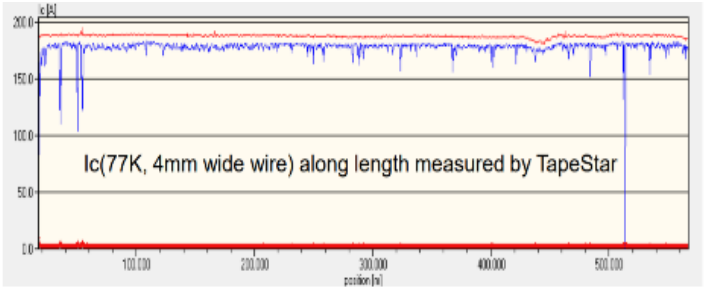
Along-tape defects



Epitaxy failure

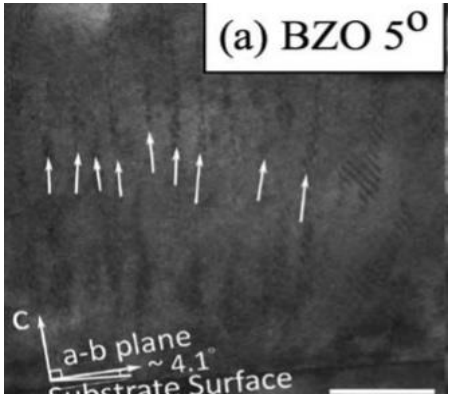




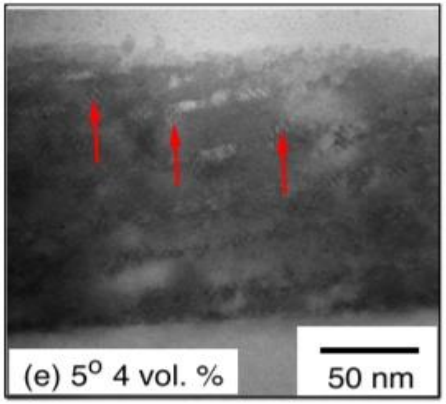


Non-uniform pinning properties, especially for correlated APC

Aligned nano-rods



Splayed-horizontal

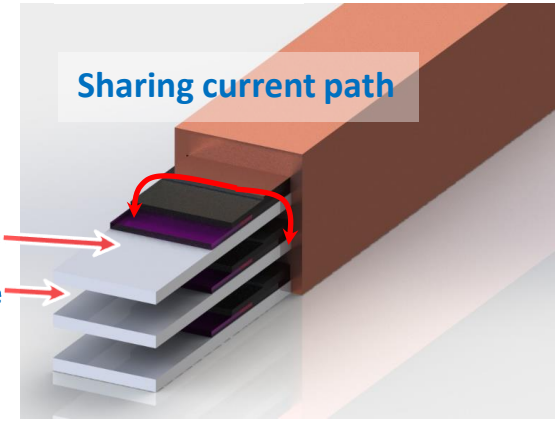


✓ We need averaging of properties within the cable

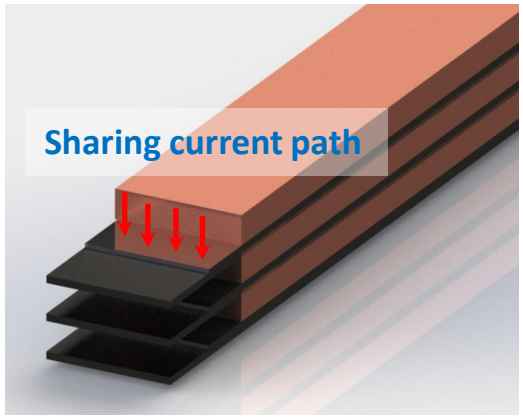
Defect—tolerant, low AC loss cable

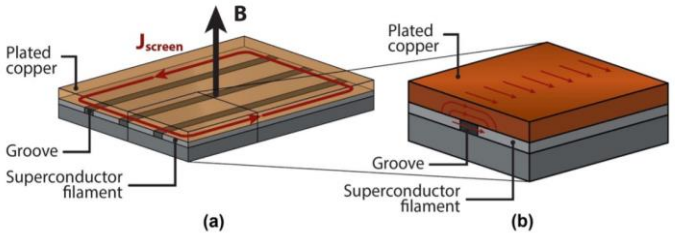
- Single-filament magnets proven difficult to protect against burnout
- Substrate prevents efficient current sharing, especially in narrow, low AC loss cables
- Multifilamentary cable is far more expensive than a single tape

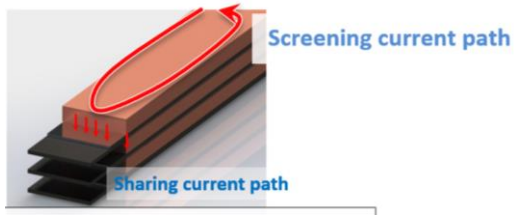
2G wire stack



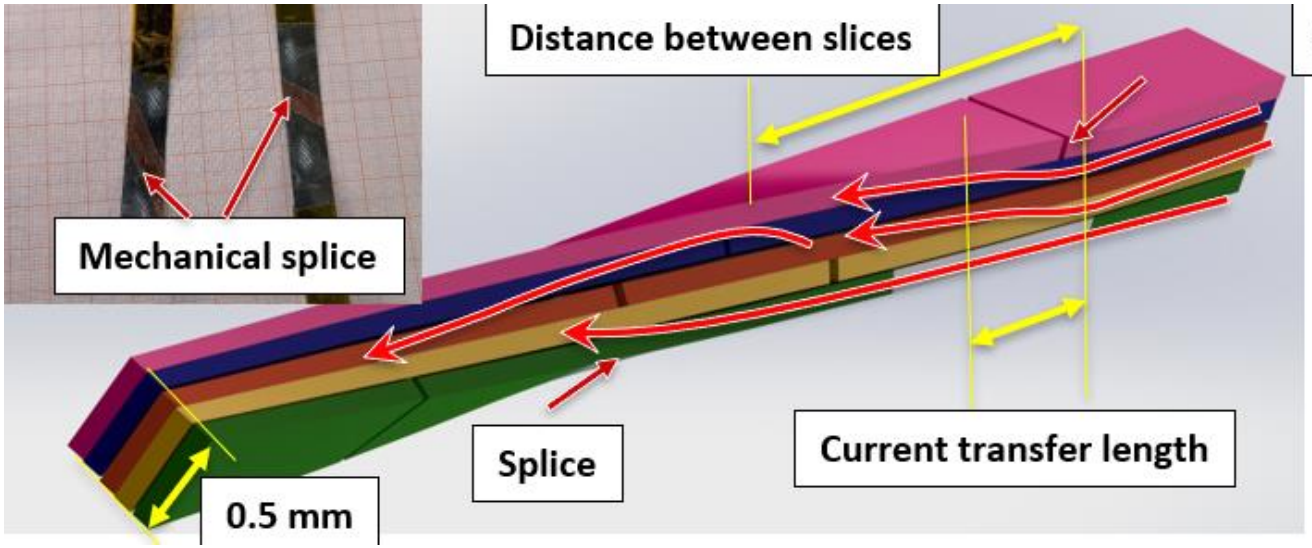
BTG exfoliated filament stack

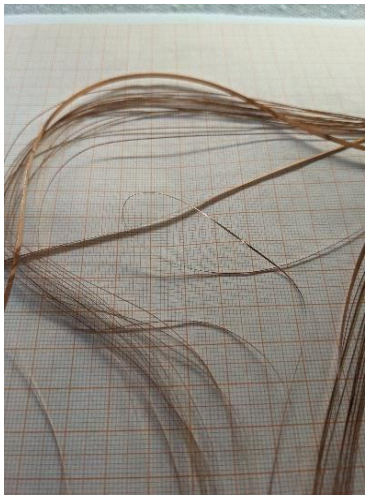






Infinite length, splice-free narrow cable

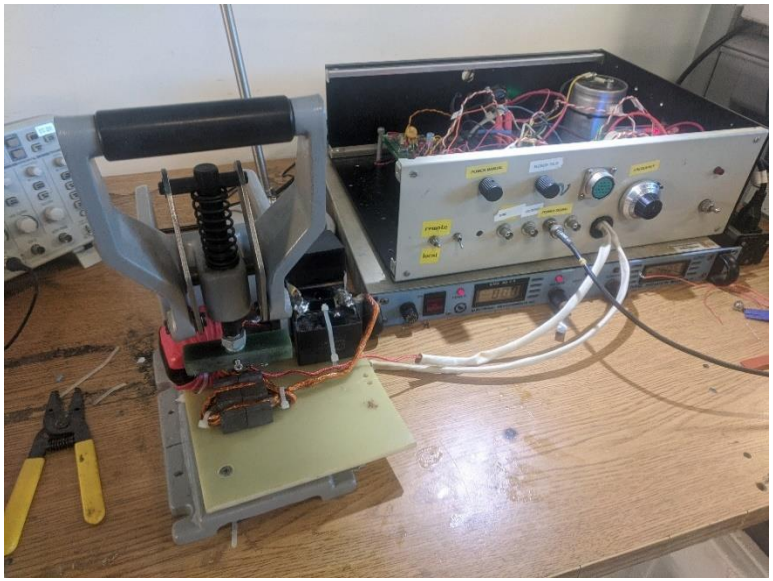


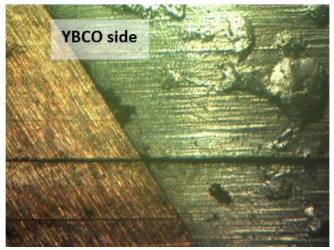


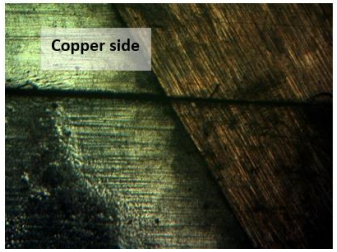
20 0.5 mm filaments

- **Human handling < 1 mm filaments is next to impossible**
- **Only wide, 10-12 mm tape is spliced and handled**

Low-profile mechanical bonding of filaments

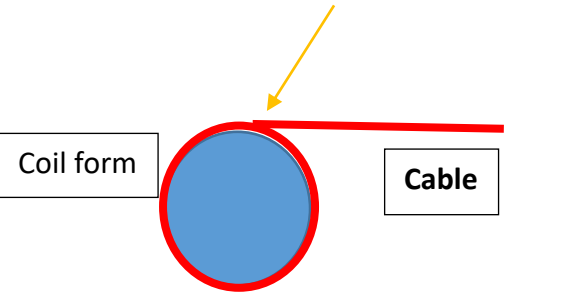




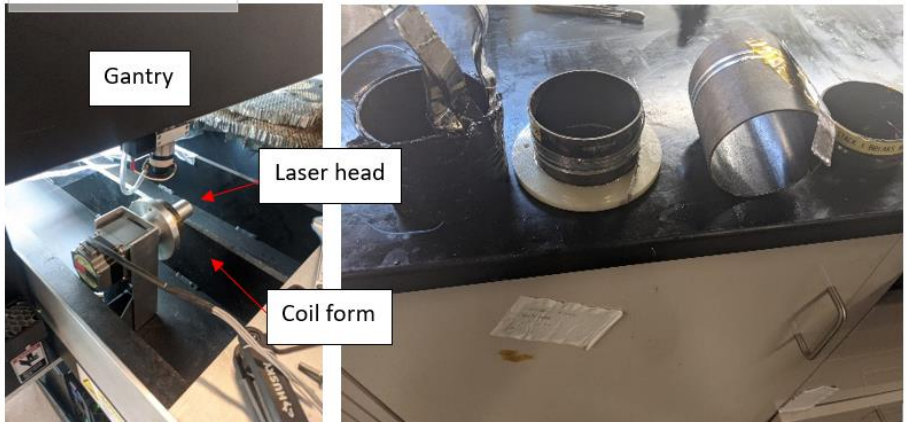


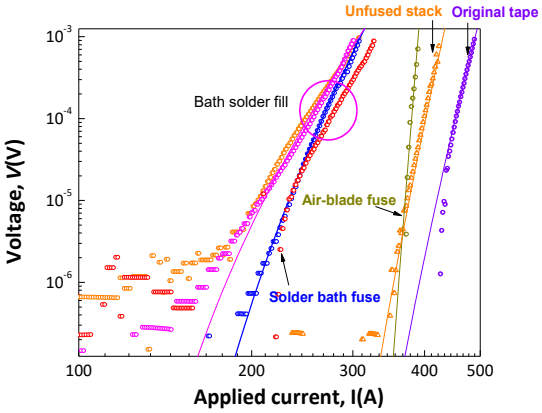
- ✓ **Low-profile mechanically strong bond: simulated “break”**

Fusing the filaments during the coil winding

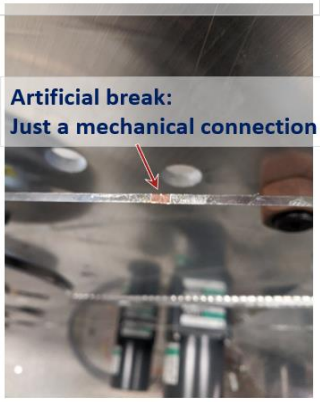


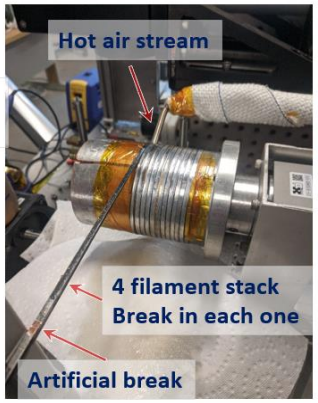
CO2 laser

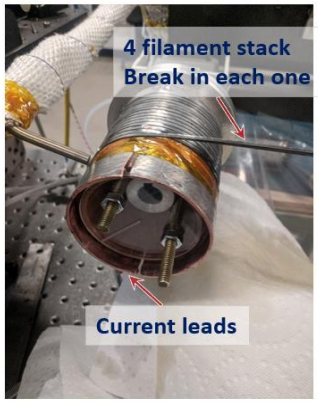




Hot air stream



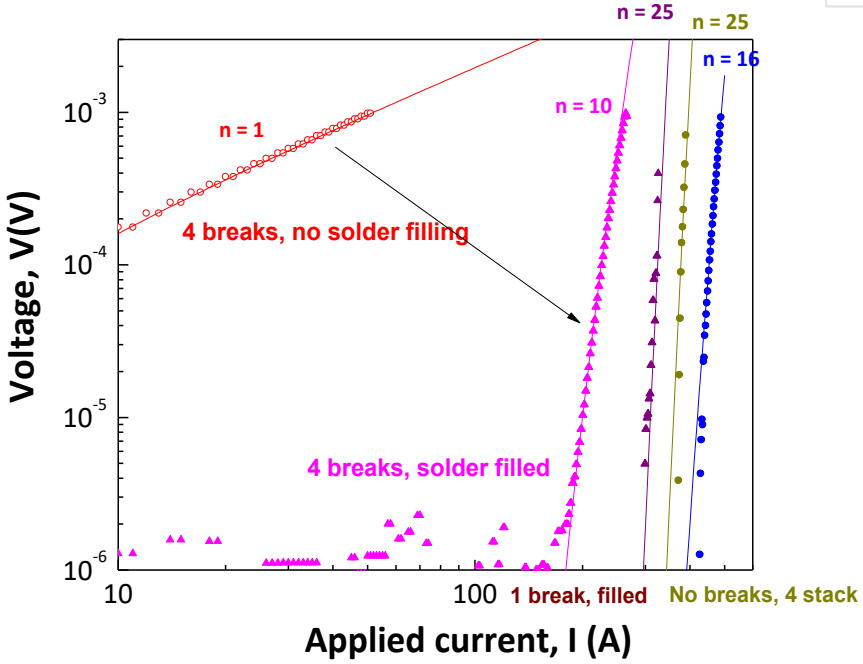


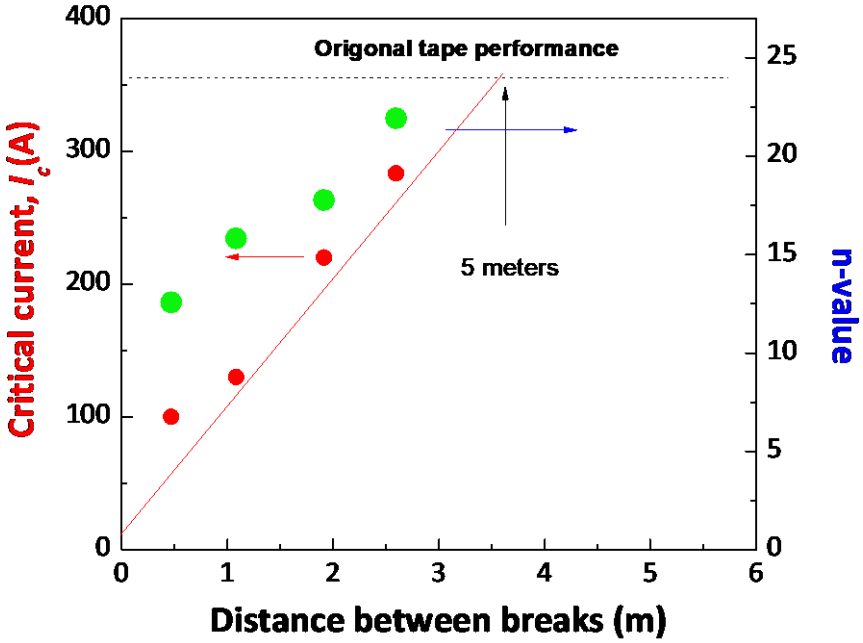


- ✓ Cable needs to be fused right before it is laid on the coilform
- ✓ Air blade method did not degrade I_c and provided the lowest contact resistance

Critical role of filament fusion

When breaks > 5 m apart, the coil would behave as if no breaks are present



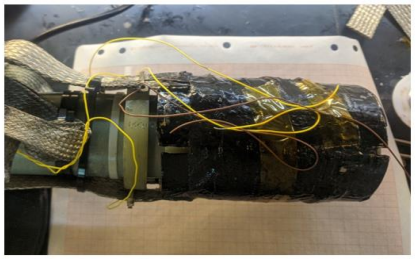


✓ Unfused filaments have negligible current sharing: just mechanical contact resistance is very high

Demonstration coil: 4 filaments, layer wound, break in each filament

As wound coil

After impregnation

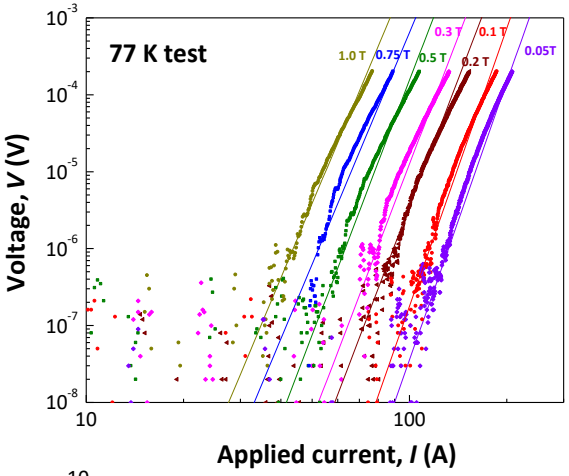


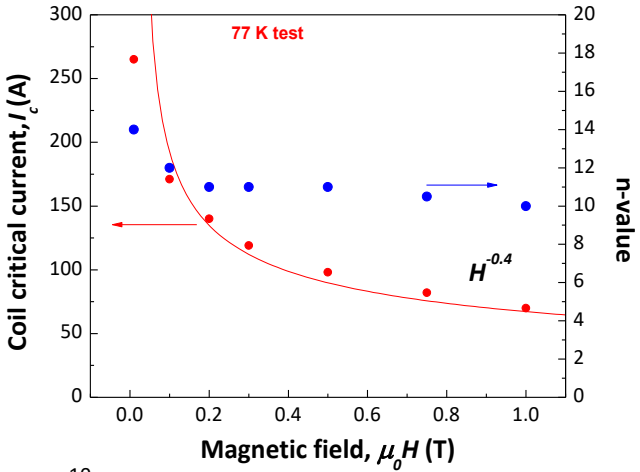
Demo coil:

- **5 meters of 2 mm 4 filament cable**
- **Each filament has a break**
- **10 cm ID**

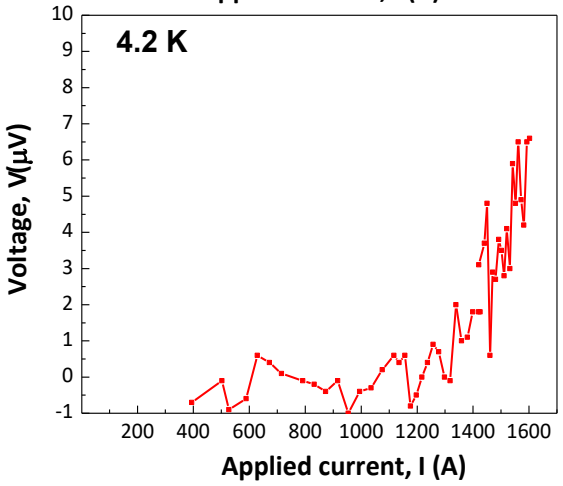
Demo coil test at 77 K and 4.2 K

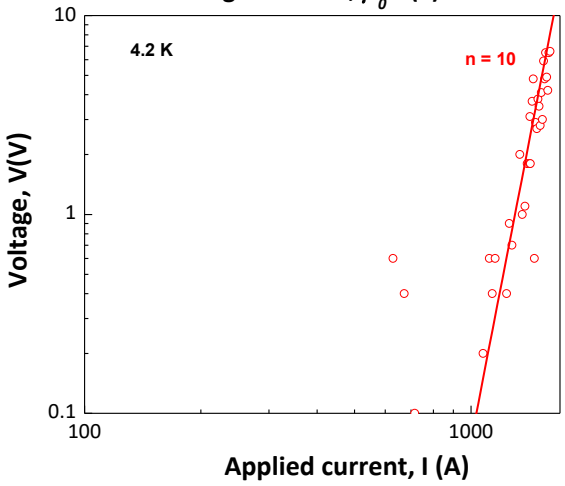
77 K





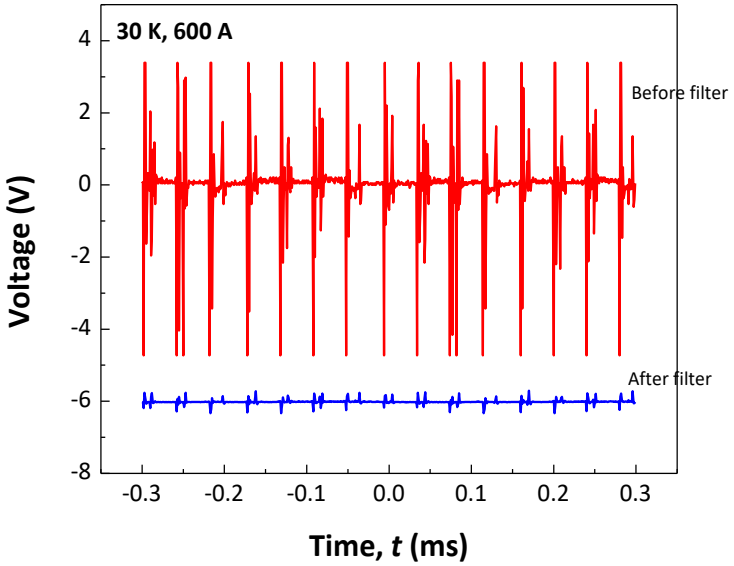
4.2 K

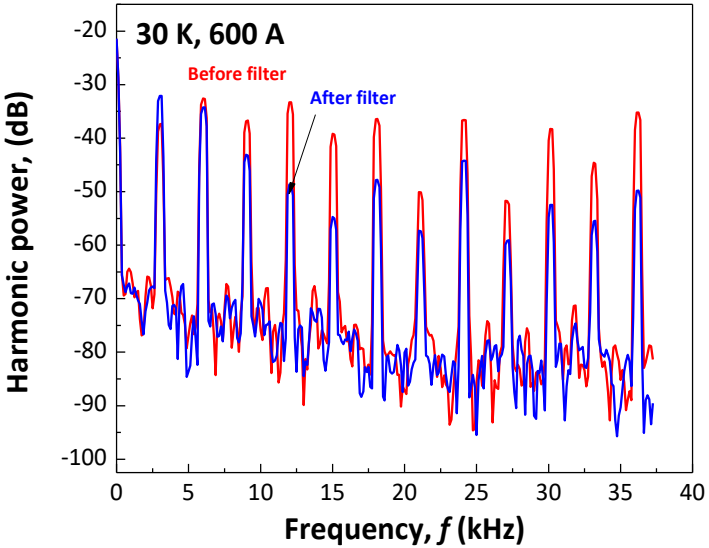




- The coil sustained 1,600 A at 4.2 K, $R < 1$ nΩ
- The n-value is limited by the discontinuities

Application: high current ripple filter for cryogenic power supply



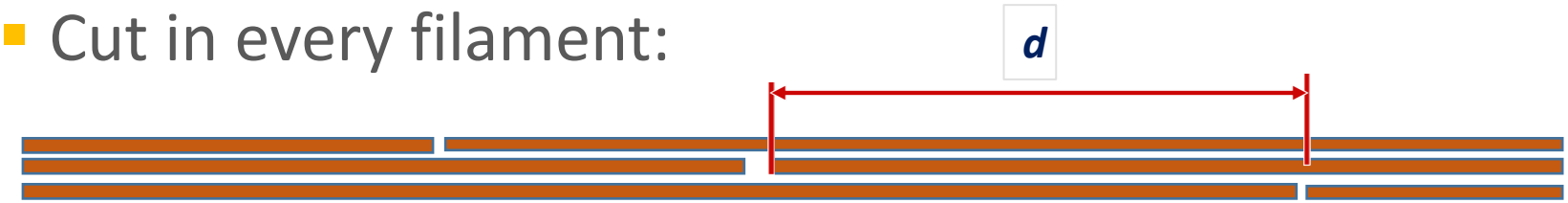


Superconducting ripple filter in the cryochamber

- ✓ Reliable operation in conduction-cooled mode under high AC ripple load because of narrow defect-tolerant cable

The proposed simple test/standard for HTS cable defect tolerance

- Cut in every filament:



- Cuts staggered at an average distance *d* from each other
- Both *n*-value and I_c are measured as a function of *d*
- The critical *d* value, $\boldsymbol{d_c}$, at which 90% of the cable performance, *n*-value and I_c, is restored
- For narrow 2G cable we estimate $d_c < 5$ m

Summary

- Defect tolerance can be achieved if resistivity between the filaments on the order of 100 $n\Omega\ cm^2$
- Mechanical contact unreliable, rapid solder fusion is critical
- We demonstrated defect tolerance by making a demo coil with each filament cut on purpose
- The coil operated up to 1,600 A (2,000 A/mm^2) at 4.2 K
- We propose a standard for defect-tolerance of 2G cables